

# FSB-B75H

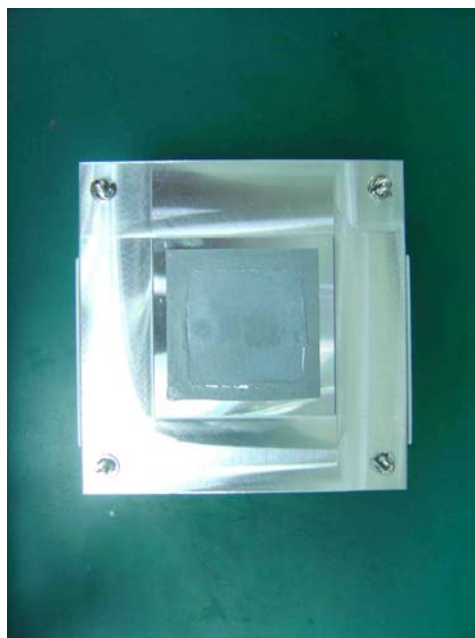
## Thermal Image Analysis Report

Summary	<input type="checkbox"/> Pass <input type="checkbox"/> Fail <input checked="" type="checkbox"/> Pass with Deviation <p style="margin-left: 20px;"><b>Comment: <u>Temperature at 2 component was estimated to be in marginal temperature point in comparion with component datasheet.</u></b></p>															
<b>Test Result Summary</b>																
	<table border="1" style="width: 100%; border-collapse: collapse;"> <thead> <tr> <th style="width: 25%;"></th> <th style="width: 25%;">Critical</th> <th style="width: 25%;">Major</th> <th style="width: 25%;">Minor</th> <th style="width: 25%;">Enhancement</th> </tr> </thead> <tbody> <tr> <td style="padding: 2px 5px;">Defect Found</td> <td style="text-align: center; padding: 2px 5px;">0</td> <td style="text-align: center; padding: 2px 5px;">0</td> <td style="text-align: center; padding: 2px 5px;">0</td> <td style="text-align: center; padding: 2px 5px;">2</td> </tr> <tr> <td style="padding: 2px 5px;">Defect Unsolved</td> <td style="text-align: center; padding: 2px 5px;">0</td> <td style="text-align: center; padding: 2px 5px;">0</td> <td style="text-align: center; padding: 2px 5px;">0</td> <td style="text-align: center; padding: 2px 5px;">2</td> </tr> </tbody> </table>		Critical	Major	Minor	Enhancement	Defect Found	0	0	0	2	Defect Unsolved	0	0	0	2
	Critical	Major	Minor	Enhancement												
Defect Found	0	0	0	2												
Defect Unsolved	0	0	0	2												

Issue date	Approval	Test Engineer
2012 / 07 / 31	Tom Lin	Rex Chang

## Sample Configuration & Quantity Under Test

- Model name : FSB-B75H A0.2
- CPU Board : FSB-B75H A0.2
- CPU : Intel i7- 3770 / 3.4GHz (QS)
- Memory : Transcend 8GB \* 2 / DDR3 1600 / Micron 2CD27D9PBC
- SATA HDD : Seagate SATA 3.5" 2TG / ST32000641AS
- BIOS : FB75AM0.3 (07/06/2012)
- Backplane: BP-206SH-P3 A1.0
- Test Software : Windows 7 / Run PassMark Burn In Test 7.0 Pro
- Power : ATX Power
- CPU Cooler :



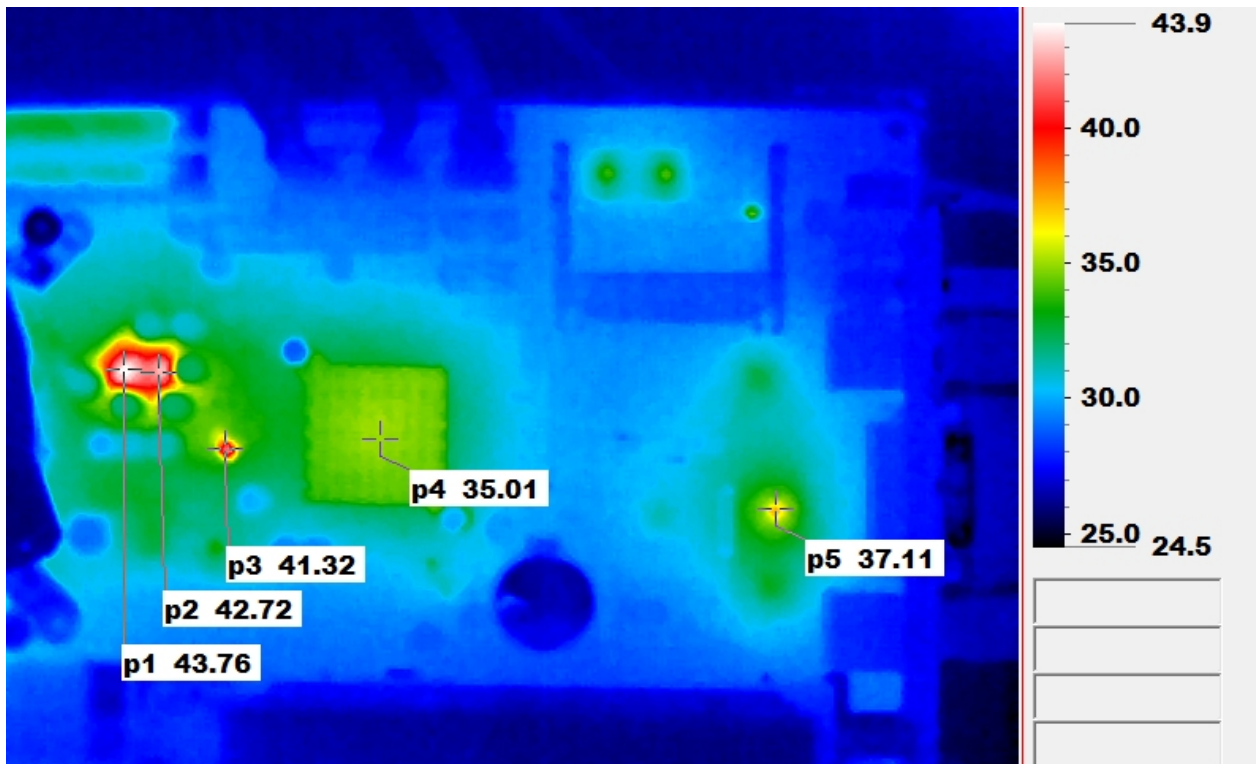
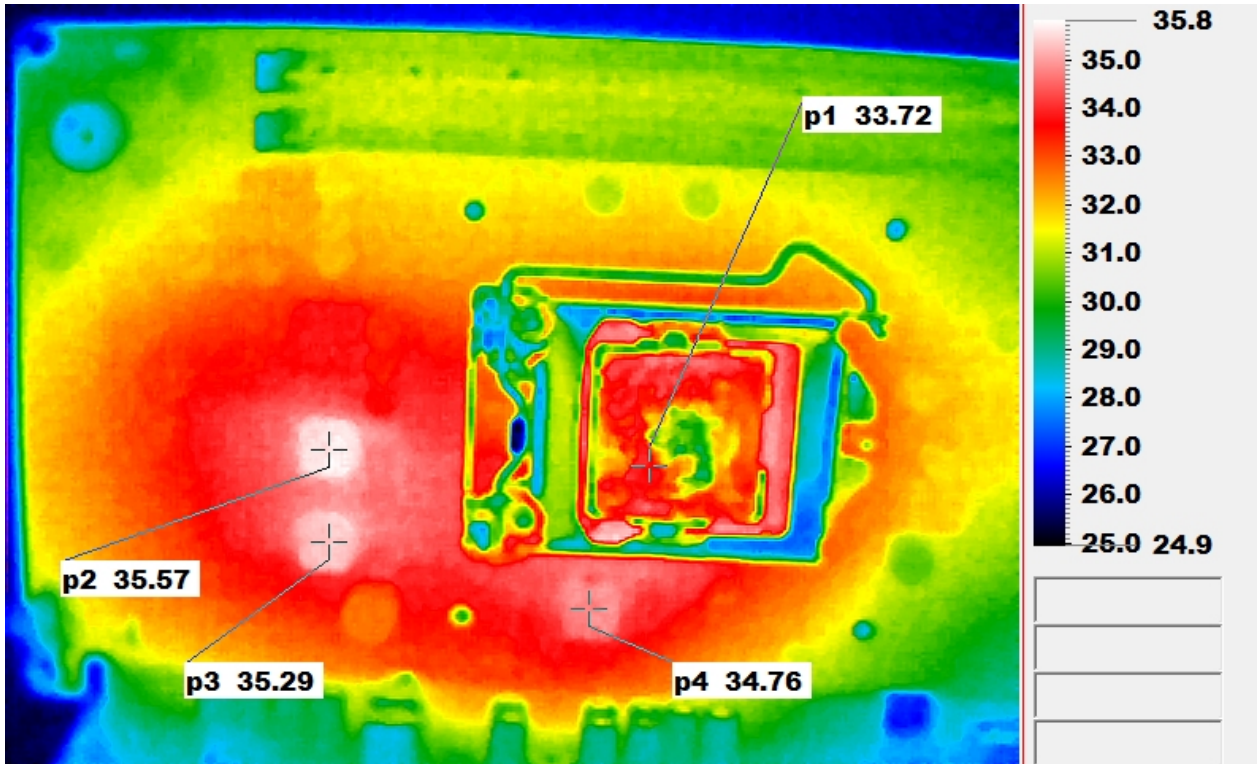
# Thermal Image Analysis

1. Test Date: 2012-07-27
2. Test Product: FSB-B75H A0.2
3. Test Site: AAEON QE Dept.
4. Temperature Measurement:
  - 4.1. 40 Channel Thermal Recorder:
    - 4.1.1 YOKOGAWA Inc,
    - 4.2.2 Model: DA100-13-1D  
Date of Calibration: 2011/10/12  
Serial Number: 12A323190
  - 4.2. IR Scanner: Infrared Camera
    - 4.2.1 NEC Avio Infrared Technologies Co., Ltd.
    - 4.2.2 Model: Thermo GEAR G100W2-D  
Date of Calibration: 2012/01/03  
Serial Number: 1051444
5. Test Condition:

Test by DA-100: 25.0°C with Cooler
6. Take Picture Time:

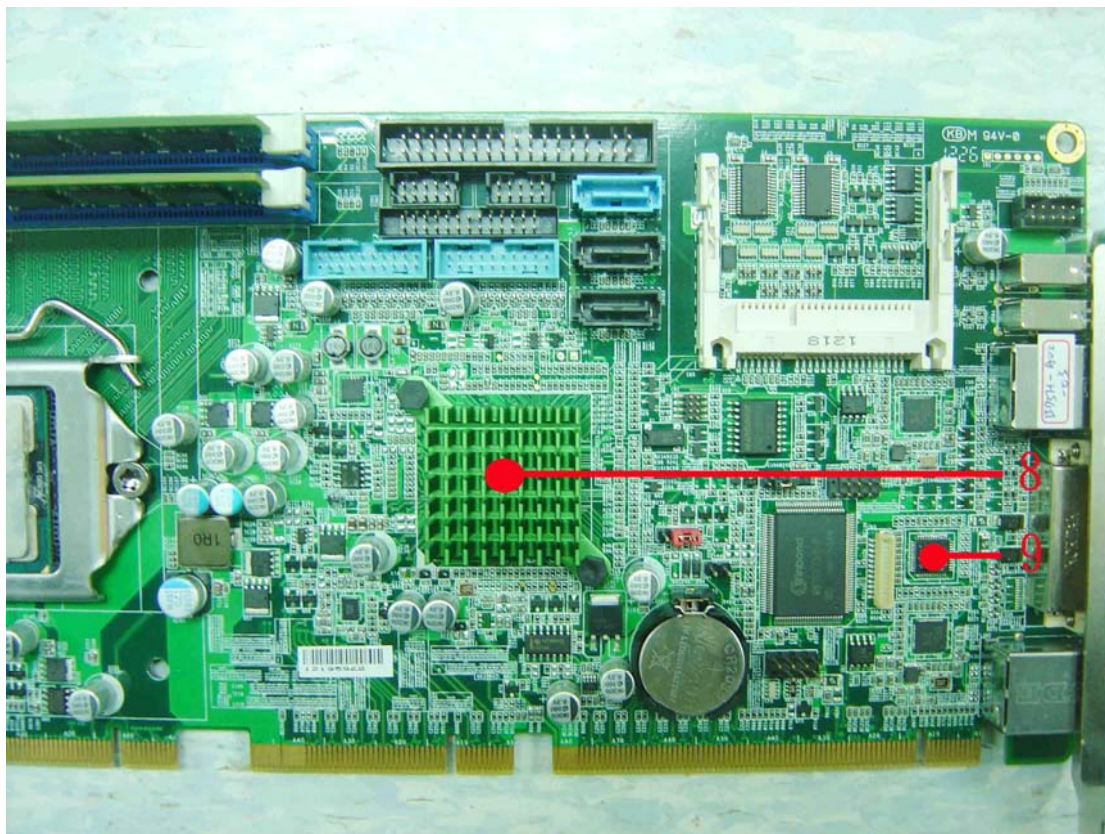
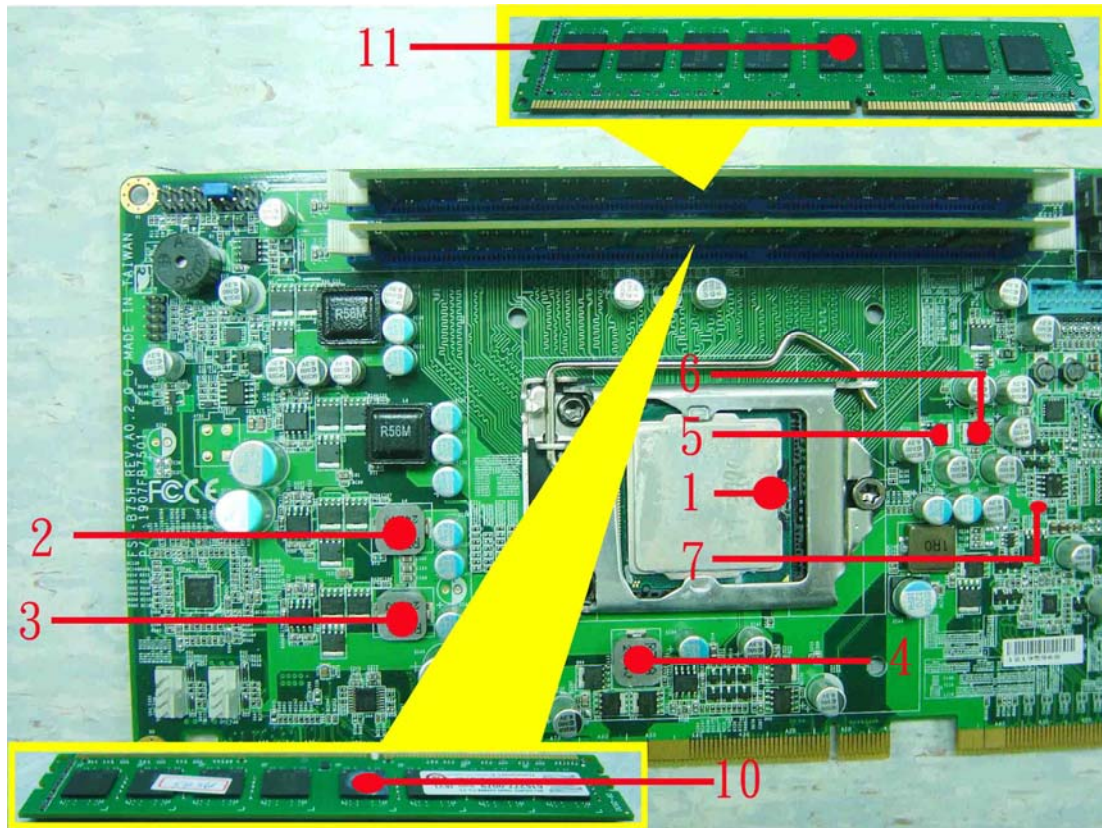
After power on 2 hours

**Temperature Profile Test:**  
**Component Side:**



### Terminal Recorder:

Measuring Thermal Couple Position :



Using YOKOGAWA / DARWIN DA100-100-13-1D test

Point	Position	Describe	Tc (*1) (°C)	Tm (*2) Measured Under		Note
				25°C	60°C	
1	U22	Intel i7- 3770 / 3.4GHz CPU	67.4	26.9	61.9	Note4
2	L6	(TF)COIL.Panasonic.ETQP4LR36AFC	130	51.2	86.2	
3	L10	(TF)COIL.Panasonic.ETQP4LR36AFC	130	43.2	78.2	
4	L13	(TF)COIL.Panasonic.ETQP4LR36AFC	130	53.2	88.2	
5	Q31	(TF)PWR. N-MOSFET.\NXP.PH7030AL	150	52.5	87.5	
6	Q33	(TF)PWR. N-MOSFET.\NXP.PH7030AL	150	50.5	85.5	
7	VR1	(TF)ADJUSTABLE PRECISION ZENER.SHUNT.NS.LM431AIM3	85	50.0	85.0	Note4
8	U19	(TF)Desktop Panther Point PCH.BGA.BD82B75 SLJ85.INTEL	108	40.4	75.4	
9	U31	(TF)Digital Video Level Shifter.ASMEDIA.ASM1442 Rev.D	85	37.5	72.5	
10	-	Memory chipset - 1	85	36.5	71.5	
11	-	Memory chipset - 2	85	37.7	72.7	

Note(\*):

- "Tc" indicates the component's case maximum temperature value specified in its datasheet.
- "Tm" indicates the measured Tc value under working environmental temperature within product specification.

3. Judgment Criteria:

- Fail :  $T_m > T_c + 5^\circ\text{C}$ ; The measured value is over specification plus margin.
- Margin :  $T_c + 5^\circ\text{C} > T_m > T_c - 10^\circ\text{C}$ ; The measured value is within specification with margin.  
For FANLESS system application, it is strongly recommended to add thermal dissipation design for better reliability.
- Pass :  $T_m < T_c - 10^\circ\text{C}$ ; The measured value is with safety margin.

4. Defect NO. [I120307QED05](#)